Search strategies for Case _No. 09/648381._
Search done in WEST. Searches done 04/1-
14/03
Ex. Andre' Stevenson

39106) and electron near beam$2

USPT
(6539106) and (array$2 or order$2)

USPT
(6539106) and table$2 and voltage$2 near contrast

USPT
(6539106) and image$2 and voltage$2 near contrast

USPT
(6091249) and (bright$2 or brightness$2)

USPT
(6539106) and (bright$2 or brightness$2)

USPT
6539106

USPT
6091249

S8677

USPT
((((semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning))and pixel$2) and $5pixel$2)) and (n or nm) and (size$2 or diameter$2)

USPT
(6091249) and pixel$2 and $5pixel$2 and (size$2 or diameter$2)

USPT
(6539106) and pixel$2 and $5pixel$2 and (size$2 or diameter$2)

USPT
(6539106) and pixel$2 and $5pixel$2 and (n or nm)

USPT
(6539106) and (controler$2 or computer$2 or processor$2) and pixel$2 and $5pixel$2

USPT
(6539106) and (controler$2 or computer$2 or processor$2)

USPT
(6091249) and pixel$2 and $5pixel$2

USPT
(6539106) and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning) and pixel$2 and $5pixel$2

S8669

USPT
(6539106) and (test$2 or testing) and (electric$2 or electrical$2 or electrically) near defect$2 and structure$2

USPT
(6539106) and (test$2 or testing) and (electric$2 or electrical$2 or electrically) near defect$2

USPT
(6091249) and (test$2 or testing) and (electric$2 or electrical$2 or electrically) near defect$2

USPT
(6091249) and (test$2 or testing) nd (electric$2 or electrical$2 or electrically) near defect$2

USPT
(6091249) and (test$2 or testing)

USPT
6539106

USPT
6091249

USPT
(((semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning))and pixel$2)and $5pixel$2) and (bright$2 or brightness)

USPT

((semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning))and pixel$2) and $5pixel$2

USPT
(6091249) and pixel$2

USPT
6091249

USPT
(semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning)) and pixel$2

USPT
((semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning))and @pyL12) and pixel$2

USPT
(semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning)) and @py<2001

USPT
semiconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning)

USPT
seimconductor$2 and voltage$2 near contrast

USPT
seimconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning)

USPT
(((seimconductor$2 voltage$2 near contrast)and (electric$2 or electrical$2) and defect$2)and image$2 and (scan$2 or scanning)) and (electric$2 or electrical$2) near defect$2

USPT
((seimconductor$2 voltage$2 near contrast)and (electric$2 or electrical$2) and defect$2) and image$2 and (scan$2 or scanning)

USPT
(seimconductor$2 voltage$2 near contrast) and (electric$2 or electrical$2) and defect$2

USPT
seimconductor$2 voltage$2 near contrast

USPT
seimconductor$2 and (electric$2 or electrical$2) and defect$2 and voltage$2 near contrast

USPT
seimconductor$2 and (electric$2 or electrical$2) and defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning)

USPT
seimconductor$2 and (electric$2 or electrical$2) near defect$2

USPT
seimconductor$2 and (electric$2 or electrical$2) near defect$2 and voltage$2 near contrast and test$2 and image$2 and (scan$2 or scanning)

USPT
(semiconductor and fluid and titration$2) and Karl near Fischer

USPT
semiconductor and fluid and titration$2

USPT
semiconductor and multicomponet$2 near fluid$2